

Finding Bugs in Concurrent Java Programs

A Comparison of Bug Detection Tools Using Mutation

Jeremy S. Bradbury, James R. Cordy, Juergen Dingel • Queen's University • Kingston, Ontario, Canada
bradbury, cordy, dingel@cs.queensu.ca

1. Motivation

- An increase in the need for concurrent software development
- Concurrent software offers a new set of challenges not present in sequential code
 - For example: deadlock and race conditions
- A concurrency bug may only occur in a very small number of execution interleavings making it extremely difficult to detect prior to deployment
- Reasoning about all possible interleavings in a program and ensuring interleavings do not contain bugs is non-trivial

Research Goal: to empirically assess different bug detection tools using seeded faults created via experimental mutation analysis.

2. Concurrent Testing vs. Model Checking

- Concurrent testing of Java with the IBM tool ConTest
 - Inserts random delays at synchronization points
 - Generates different interleavings each time a program is run
- Model checking of Java with Java PathFinder or Bandera/Bogor
 - Exhaustively searches the entire state space of a model (i.e., all interleavings)
 - Allows for the analysis of assertions and deadlock detection

3. Experimental Mutation Analysis

- Use mutation to empirically assess testing, static analysis, model checking, and dynamic analysis [5,6]

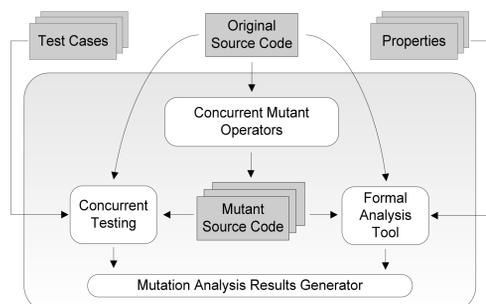


Figure 1: Experimental mutation analysis for comparing testing and model checking

4. Mutation Operators for Concurrent Java

- **ConMAN** (Concurrency Mutation Analysis) operators for Java (J2SE 5.0) [2,3]
- 24 ConMAN operators based on real concurrency bug patterns
- Implemented in TXL – a source transformation language
- The classes of operators include: modifying critical regions, keywords, concurrency method calls, parameters of concurrency method calls, and switching concurrency objects
- An example of a **Shrink Critical Region (SKCR)** mutation:

Original Code:

```
<statement n1>
synchronized (this) {
// critical region
<statement c1>
<statement c2>
<statement c3>
}
```

SKCR Code:

```
<statement n1>
//critical region
<statement c1>
synchronized (this) {
<statement c2>
}
<statement c3>
<statement n2>
```

- An example of a **Remove Static Keyword (RSTK)** mutation:

Original Code:

```
public static synchronized void bMethod() { ... }
```

RSTK Mutant:

```
public synchronized void bMethod() { ... }
```

5. ExMAN Framework

- **ExMAN** (Experimental Mutation Analysis) Framework [1,4]
- A realization of our experimental mutation analysis approach
- A reusable implementation for building different customized mutation analysis tools for comparing different quality assurance techniques

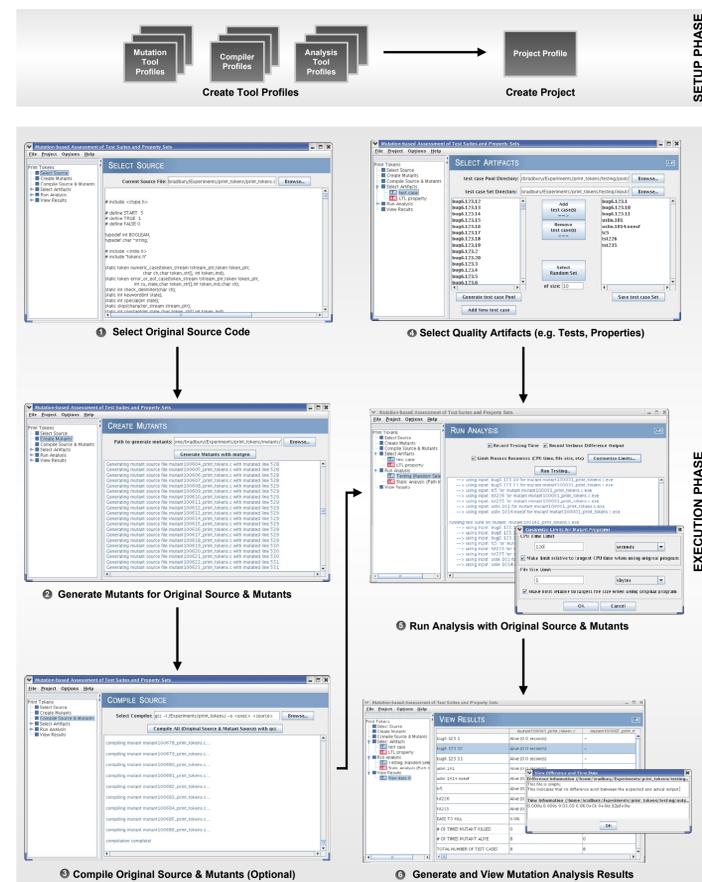


Figure 2: The ExMAN process

6. Comparing Testing and Model Checking

- ExMAN is customized to compare testing with ConTest and model checking with Java PathFinder or Bandera/Bogor
- The ConMAN plug-in is used with ExMAN to generate the faulty program versions
- Our current experiment uses a set of 7 programs from a benchmark of concurrent Java applications maintained at the IBM Haifa Labs

7. References

- [1] ExMAN Framework website (<http://www.cs.queensu.ca/~bradbury/exman/>)
- [2] ConMAN Operators website (<http://www.cs.queensu.ca/~bradbury/conman/>)
- [3] "Mutation Operators for Concurrent Java (J2SE 5.0)", J.S. Bradbury, J.R. Cordy, and J. Dingel, In *Proc. of the 2nd Workshop on Mutation Analysis (Mutation 2006)*, Nov. 2006, 10 pp. (to appear)
- [4] "ExMAN: A Generic and Customizable Framework for Experimental Mutation Analysis", J.S. Bradbury, J.R. Cordy, and J. Dingel, In *Proc. of the 2nd Workshop on Mutation Analysis (Mutation 2006)*, Nov. 2006, 6 pp. (to appear)
- [5] "Using Mutation for the Assessment and Optimization of Tests and Properties", J.S. Bradbury, *Doctoral Symposium being held in conjunction with the International Symposium on Software Testing and Analysis (ISSTA 2006)*, Jul. 2006, 4 pp.
- [6] "An Empirical Framework for Comparing Effectiveness of Testing and Property-Based Formal Analysis", J.S. Bradbury, J.R. Cordy, and J. Dingel, In *Proc. of the 6th International ACM SIGPLAN-SIGSOFT Workshop on Program Analysis for Software Tools and Engineering (PASTE 2005)*, pages 2–5, Sept. 2005.